Attorney Docket No. 9180-30

**PATENT** 

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re: Jong-Rong Jan et al;

Application No.: not yet assigned Filed:

concurrently herewith

For:

METHODS OF SELECTIVELY BUMPING INTEGRATED CIRCUIT

SUBSTRATES AND RELATED STRUCTURES

Date: February 17, 2004

MAIL STOP PATENT APPLICATION Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

## INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(b)

Sir:

Attached is a list of documents on Form PTO-1449, together with a copy of any listed foreign patent document and/or non-patent literature. A copy of any listed U.S. patent and/or U.S. patent application publication is not provided herewith in accordance with the waiver by the U.S. Patent and Trademark Office of requirements under 37 C.F.R. § 1.98(a)(2)(i) for all U.S. national patent applications filed after June 30, 2003 and for all international applications that have entered the national stage under 35 USC § 371 after June 30, 2003.

It is requested that these documents be considered by the Examiner and officially made of record in accordance with the provisions of 37 C.F.R. § 1.56 and Section 609 of the MPEP.

No fee is believed due. However, the Commissioner is hereby authorized to charge any deficiency or credit any overpayment to Deposit Account No. 50-0220.

Respectfully submitted,

Registration No. 38

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Substitute form 1449A/PTO				Complete if Known			
				Application Number	not yet assigned		
INFORMATION DISCLOSURE				Filing Date	concurrently herewith		
STATEMENT BY APPLICANT			T	First Named Inventor	Jong-Rong Jan et al;		
(use as many sheets as necessary)				Group Art Unit	not yet assigned		
				Examiner Name	not yet assigned		
Sheet	1	of	1	Attorney Docket Number	9180-30		

	T			AND PATENT PUBLICATIONS	
Examiner Initials*	Cite No.	U.S. Patent	Document	Name of Patentee or Applicant of Cited  Document	Date of Publication of Cited Document MM-DD-YYYY
		Number	Kind Code (if known)		
	1.	US-3,625,837		Nelson et al;	12/07/1971
	2.	US-5,130,275		Dion	07/14/1992
	3.	US-5,211,807		Yee	05/18/1993
	4.	US-5,462,638		Datta et al;	10/31/1995
	5.	US-5,470,787		Greer	11/28/1995
	6.	US-5,471,092		Chan et al;	11/28/1995
	7.	US-5,759,437		Datta et al;	06/02/1998
	8.	US-5,796,168		Datta et al;	08/18/1998
	9.	US-5,937,320		Andricacos et al;	08/10/1999
	10.	US-6,015,505		David et al;	01/18/2000
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	12.	US-6,332,988		Berger, Jr. et al;	12/25/2001
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Examiner Initials*	Cite No.	ì	Foreign Patent D		Document of Cited	Date of Publication	T	
		Office	Number	Kind Code (if known)		of Cited Document MM-DD-YYYY	ed Document	
	<u> </u>	<u> </u>	ОТН	ER NON PATEN	T LITERATURE DOCUMENTS			
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published						
13. R.B. Danzl and Allen McLaurin; "The Use of Concentrated Hydrogen Peroxide for the Remote TiW ARC from Aluminum Bond Pads" IEEE/CPMT Int'l Electronics Manufacturing Technolog Symposium (1997) pp 99-104.								
	14.	Akira Furuya and Yoshio Ohshita; "Ti concentration effect on adhesive energy at Cu/TiW interface";  Journal of Applied Physics, Vol. 84, No. 9, (Nov 1998) pp 4941-4944.						
	15.	<ol> <li>Julia Hawley and Van-Vo; "Solutions to Catastrophic Yield Problems in MCM-D Interconnect Production"; 1998 International Conference on Multichip Modules and High Density Packaging; pp 118- 123.</li> </ol>						
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Examiner Signature	Date Considered	
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